

**Amendments to the Specification**

Please replace the paragraph on page 6, lines 4-10 with the following amended paragraph:

In order to achieve the above-mentioned objective, in the present invention, in a parameter correction circuit included in a semiconductor integrated circuit, a reference parameter, which has a preliminarily known parameter value, is connected to the semiconductor integrated circuit, and a current is allowed to flow through this reference parameter from a mirror circuit, so that the current value of the mirror circuit is found, and based upon the resulting value, a variable parameter that is a correction target is corrected and made less susceptible to production deviations of the mirror circuit and the like.

Please replace the paragraph on page 13, line 7 with the following amended paragraph:

Fig. 11 shows a loop characteristic of the PLL circuit in the conventional semiconductor integrated circuit.

Please replace the paragraph on page 22, lines 2-6 with the following amended paragraph:

Fig. 2C shows a structure of a parameter correction circuit in accordance with the third embodiment of the present invention. In this embodiment, a capacitor element is used as the parameter; ~~that is, a capacitor element C1 or C2 that the filter circuit 104 of the PLL circuit 101 shown in Fig. 1~~ has is not externally included, but included inside the LSI 100 as a variable capacitor element.

Please replace the paragraph on page 45, lines 18-20 with the following amended paragraph:

~~Wherein, the~~ The oscillator circuit **30** shown in Fig. 8 ~~Fig. 30~~ is used as an oscillator circuit using the variable inductor element in the present invention, but the present invention is, of course, applicable to an oscillator circuit having another structure.